

Self triggered Pulse Amplification and Digitization asIC

THE TRD READOUT ASIC 'SPADIC'

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http://spadic.uni-hd.de





Original Goals of SPADIC Development (~2006)

TRD readout (electron ID & tracking):

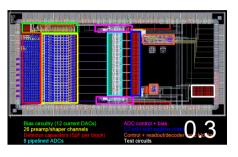
- Event assignment (via time)
- e/π separation via signal shape
 - Shape & time → sample pulse → ADC
 - High rate \rightarrow eliminate ion tail \rightarrow (digital) filter
 - High rate → large data volume → high speed IF (CBMNet)
- Concept similar to PASA + ALTRO/TRAP (2 chip solutions)
- Aim at a Single Chip Solution without external IP
 - Low cost
 - High flexibility to implement what is needed
 - Simple chip mounting (avoid costly Multi-Chip Modules)
 - Compact
 - Get (some) radiation tolerance from DSM technology (UMC018)

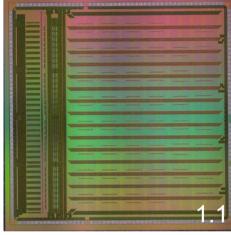


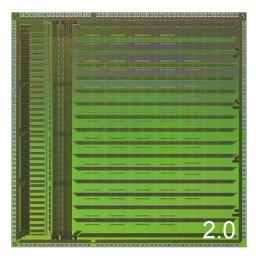


History

- 2006: Building blocks (Charge Amplifier, ADC)
- 2009: SPADIC 0.3: Full channels





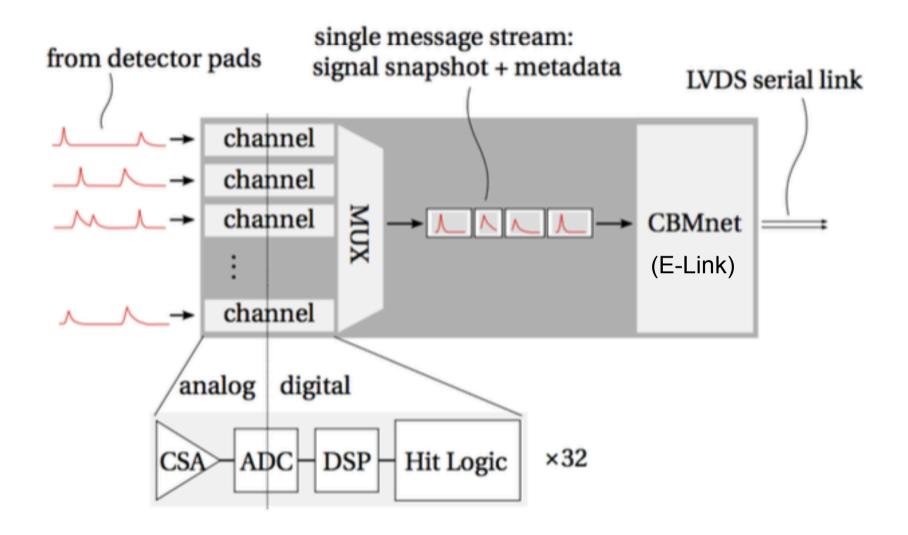


- 2011: SPADIC 1.0: Full 32 channel chip with CBM-Net
- 2015: SPADIC 1.1: Small Bug Fixes (CSA, link, hit detector)
- 2016: SPADIC 2.0: Change in shaping time and sampling, E-Link Interface (from STS-XYTER team)
- Effort: 1 FTE / year (Tim Armbruster, Michael Krieger)





Block Diagram







Key Parameters

 $5 \times 5 \, \mathrm{mm}^2$ Chip Size

Channels 32

Total Power $600 \,\mathrm{mW}$

Peaking time of analogue part 80/160 ns (ENC ~800e @ 90ns, 30 pF)

 $(EnOB \sim 7.5 Bit)$ ADC resolution 9 bit.

 $24/16\,\mathrm{MHz}$ ADC Sampling frequency

FIR Filter stages (1st order)

Technology UMC 180nm

Transistor count $\approx 2.5 \,\mathrm{M}$

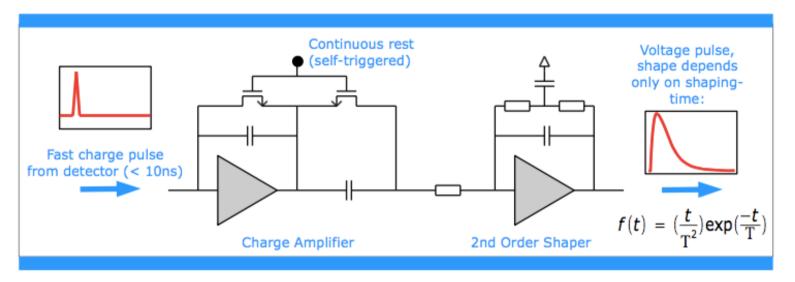
Features

- Hit Finder with several modes (absolute / differential threshold)
- Pulse Sampling with arbitrary pulse picking pattern
- Neighbor Trigger (via LVDS links)
- Time ordering of hits (per 16 channels)





Charge Amplifier / Shaper



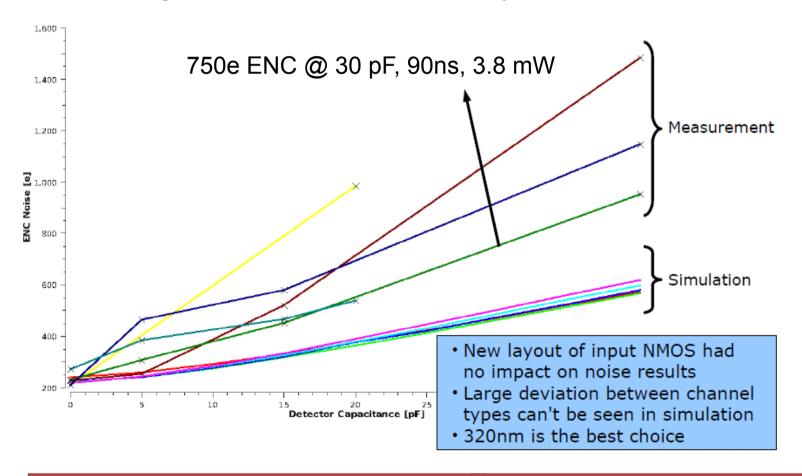
- Positive and negative polarity available, Q_{max} = ±75 fC
- Pole-Zero compensation
- CR-RC Shaping
- $P_{CSA} = 3.8 \text{ mW (pos.)} / 10 \text{ mW (neg., not optimized)}$
- ENC ~ 200 e⁻ + 20 e⁻ / pF
- Pulse Monitoring on analogue pad





CSA Noise

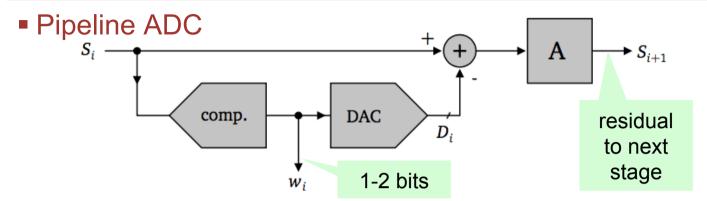
- Simulated/measured noise for varying transistor length (180-460 nm) do not match (no L-dependence in simulation!)
- Best length of 320 nm determined by test structures



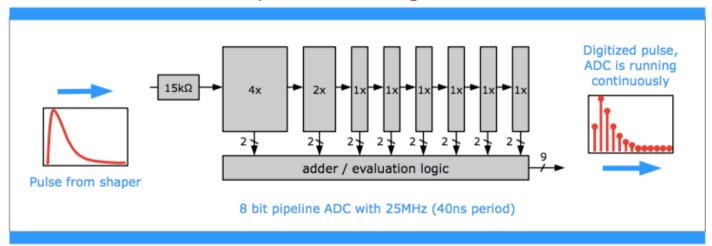




ADC



Scaled Currents for power saving



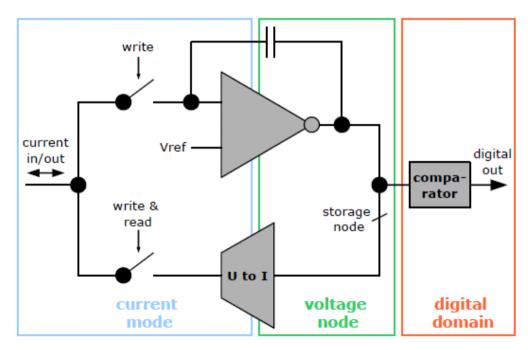
- 1.5 Bits / stage (error correction)
- 24 MSpS, 9 Bit design





(ADC Current Memory Cell)

- Current Mode operation
- Novel storage cell:
 - Virtual ground
 - No Early effect
 - Can 'mirror' current for comparator

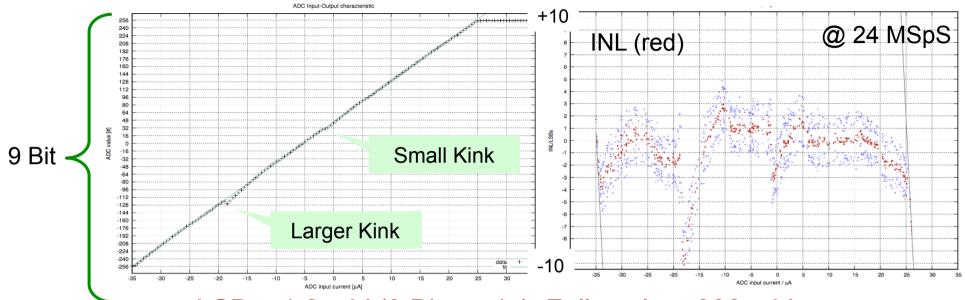


Inherited' from Belle Project (I. Peric), modified by T.A.

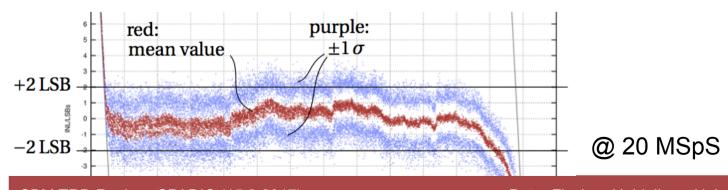




ADC Characteristics

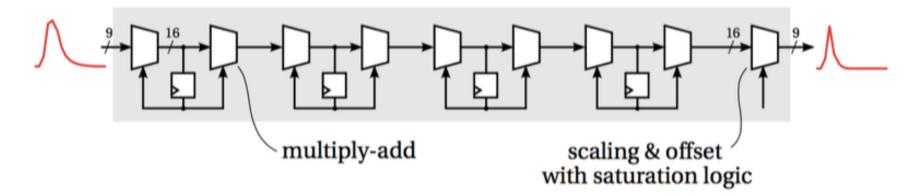


- LSB = 1.8 mV (9 Bit mode), Full scale = 933 mV
- Noise = 0.72 LSB (9 Bit mode)
- After correction, EnOB ~ 7-7.5 Bit (better at lower speed)





Digital Filter



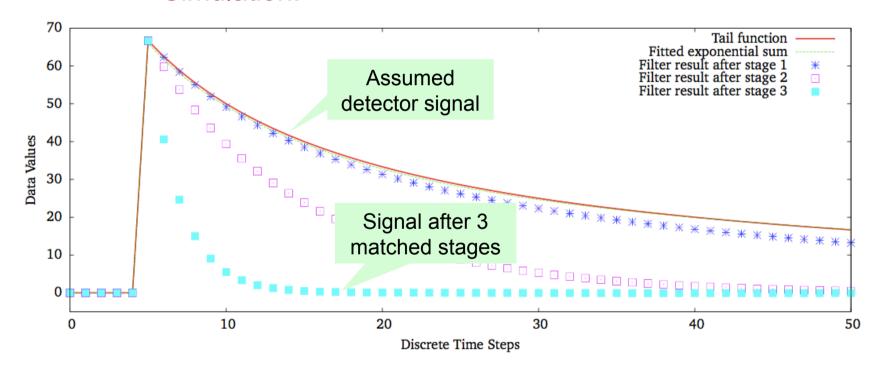
- FIR filter, 4 stages
- Widths of internal processing and coefficients optimized
 - (Diploma M. Krieger)
- Multipliers consume significant digital logic resources





Filter Operation

- Can be used to eliminate ion tails
- Can be switched off
- Simulation:



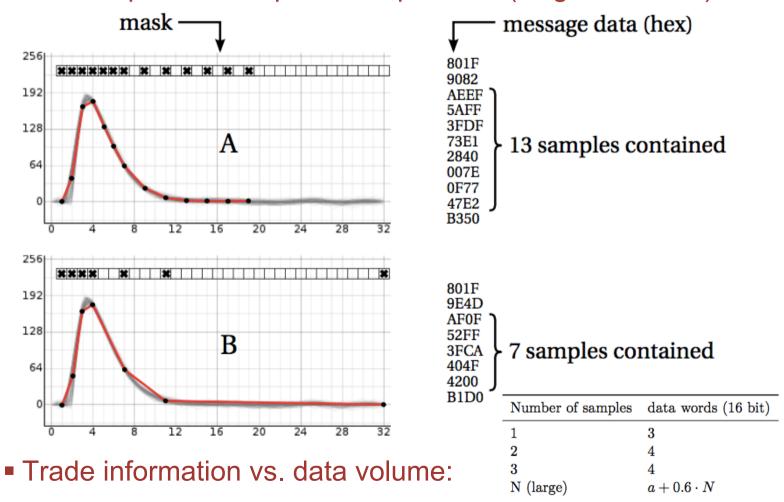
Note: filter adds noise ('high-pass' function)





Sample Picking

- Mask register allows to pick samples of a pulse to read out
- Pre-samples before pulse are possible (→ get baseline)

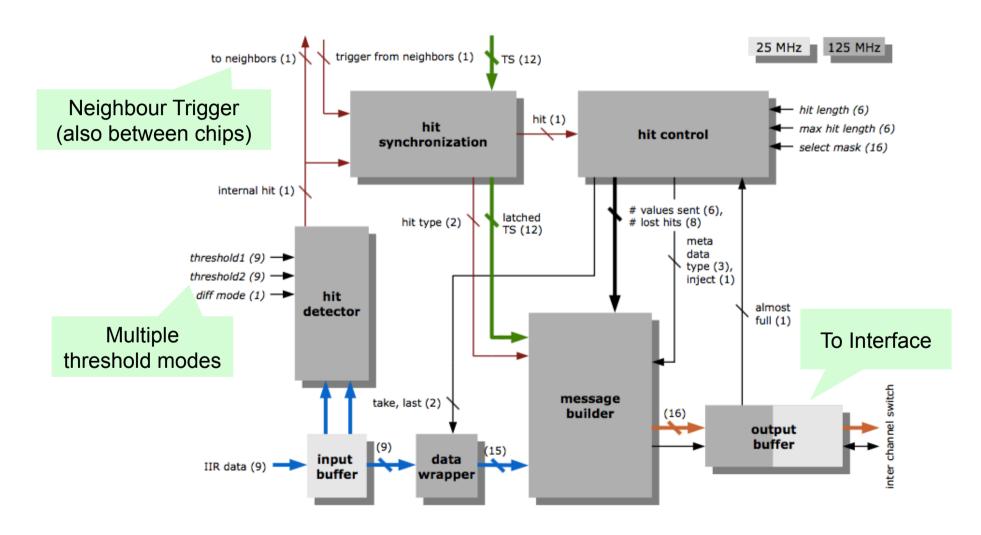






Data Processing

• Quite Complex

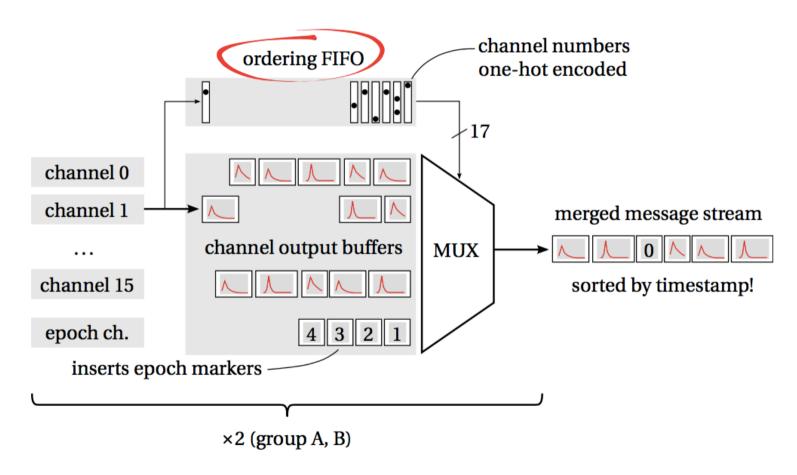






Ordering FIFO

Sequential data is ordered by time stamps!

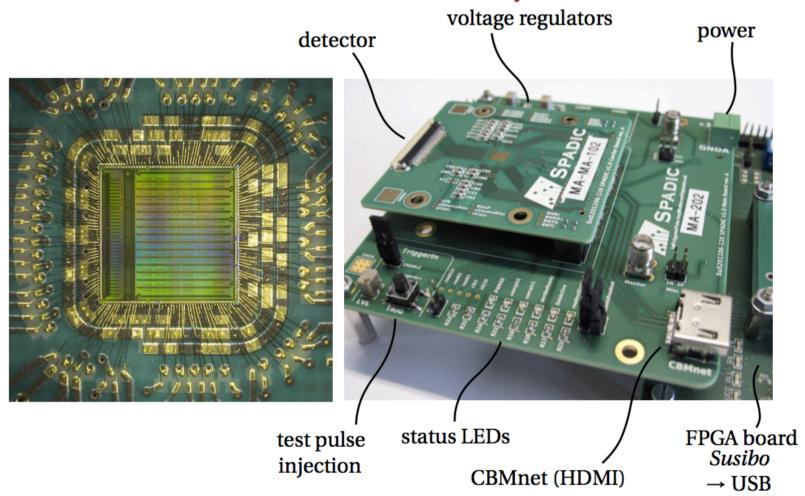






Readout Setup

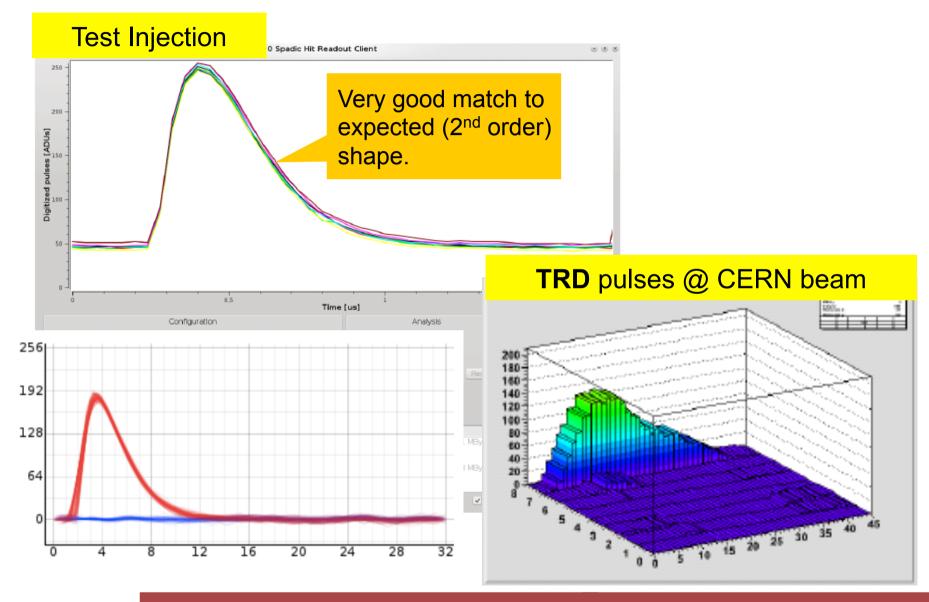
- Several systems / boards build for various chips
- Measured via USB2.0 readout system 'SUSIBO'







Sampled Pulses



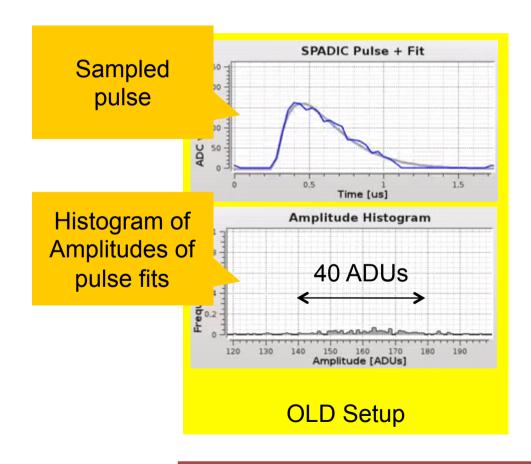




Readout Boards Affect Quality A LOT

- Same ASIC, Readout, Detector connected
- Test pulse injections
- www.youtube.com/watch?v=tK7Hm2MSg3Y





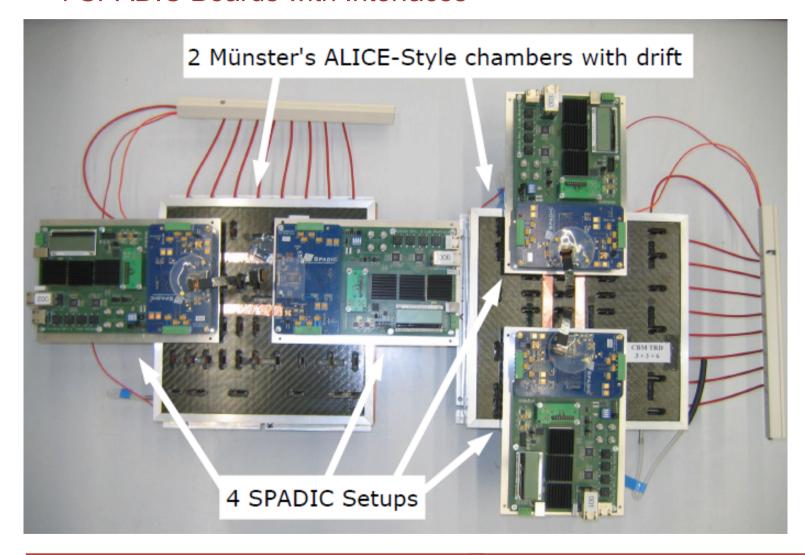






Test Beam Setup

4 SPADIC Boards with Interfaces

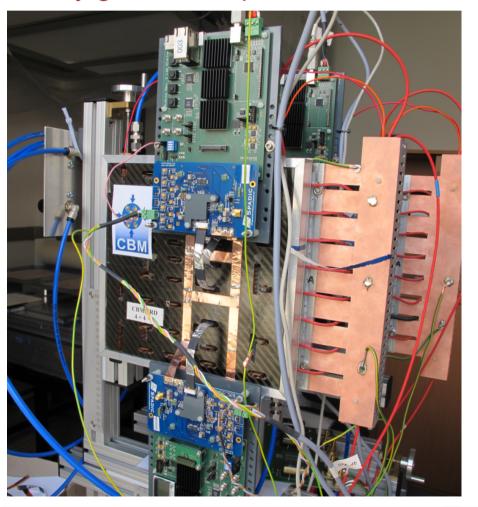


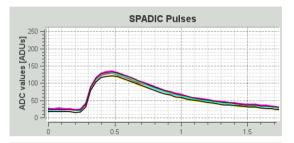


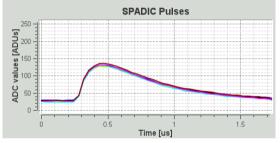


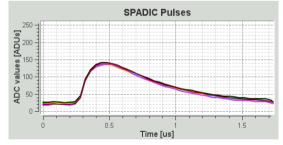
SPADICs on Detectors

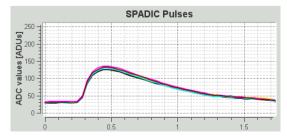
- 'Münster' chambers with SPADIC1.0
- Very good noise performance in lab















SPADIC 2.0

- Very close to final chip
- Main motivation: CBMNet → STS-XYTER protocol (E-Link)
- Changes w.r.t. SPADIC 1.0 / 1.1:

Changes in SPADIC 2.0

CBMnet replaced by STS-XYTER protocol

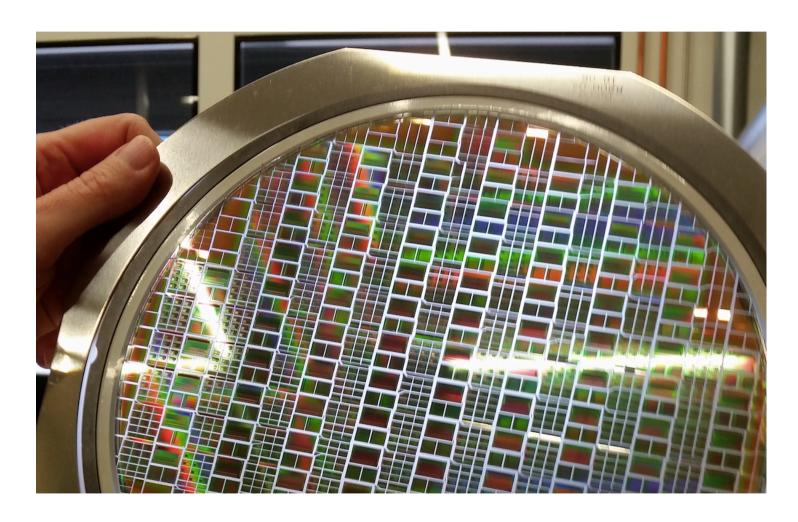
- **Before:** 25 MHz sampling rate, $\tau = 80 \text{ ns} = 2 T$ **Now:** 16 MHz sampling rate, $\tau = 250 \, \text{ns} = 4 \, T$
- **Before:** Several SPADIC words in one CBMnet packet **Now:** One SPADIC word in one *uplink frame*
- **Before:** CBMnet packet buffers DLM needed for synchronization **Now:** No buffering – all *frames* intrinsically deterministic – unified configuration and synchonization interface
- Register size changed from 16 to 15 bits some registers were split
- No triggering of epoch markers needed anymore
- One more "presample"





SPADIC 2.0 Production

■ SPADIC 2.0 was produced as part of a CBM engineering run







SPADIC 2.0 packaging

- SPADIC 1.x were in expensive 'prototype' package
- SPADIC 2.0 is in cheap plastic QFP208 package
 - 2 \$ / piece in large quantities
- 200 packaged chips are available



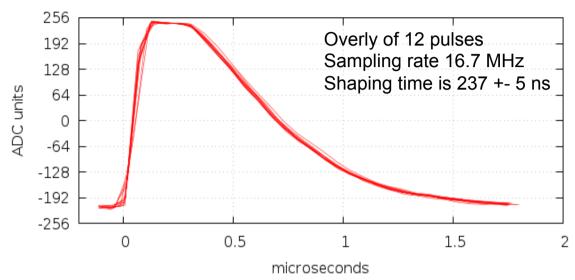
Photo: Cruz Garcia





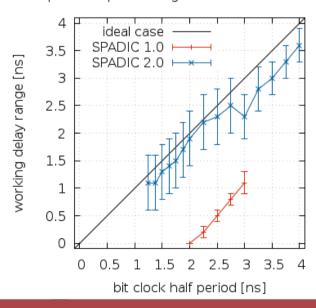
SPADIC 2.0 Works as Expected

Sampled pulses:



Comparison uplink timing tolerance SPADIC 1.0 vs 2.0

Timing tolerance of serial interface is largely improved wrt. SPADIC 1.0:







Next Steps

- Enough SPADIC2.0 available for upcoming detector tests
- Results will tell us if changes are needed
 - e.g. amplifier shaping time, gain
- Planned changes for 'final' SPADIC2.1 are related to data format / volume:

Revision of data format

- Currently, the STS-XYTER protocol is not efficiently used (one 16-bit word in one 23-bit frame – 7 bits per frame wasted)
- Some of the transmitted data is redundant (e.g. group ID mirrors information already known further "up" in the DAO chain)
- Investigate more clever ways to reduce the amount of data (e.g. combine data from neighboring channels which belong together anyway)





Summary

- The 32 channel SPADIC is available since several years
- It contains Charge Amplifier, ADC, Filter, a flexible hit detection and self-triggered serial readout
- SPADIC has been used for several detector tests successfully
- Latest SPADIC2.0 implements E-Link protocol
- Chip is functioning
- Expected changes for 'hopefully final' SPADIC2.1 are small.